

**Search Notes**

Application/Control No.

10/647,433

Examiner

Binh X. Tran

Applicant(s)/Patent under  
Reexamination

MIMURA ET AL.

Art Unit

1765

**SEARCHED**

Class	Subclass	Date	Examiner
438	711	10/6/2005	BT
438	719	10/6/2005	BT
438	728	10/6/2005	BT
438	729	10/6/2005	BT

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
Search keywords and inventor's name using EAST	10/6/2005	BT

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner